

PCN Number:	20150327001	PCN Date:	04/02/2015
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Title:	Qualification of New Lead Frame Base Material for Selected Devices		
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Customer Contact:	PCN Manager	Dept:	Quality Services
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Proposed 1st Ship Date:	07/02/2015	Estimated Sample Availability:	Provided upon Request
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Change Type:			
<input type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Assembly Process
<input type="checkbox"/>	Design	<input type="checkbox"/>	Electrical Specification
<input type="checkbox"/>	Test Site	<input type="checkbox"/>	Packing/Shipping/Labeling
<input type="checkbox"/>	Wafer Bump Site	<input type="checkbox"/>	Wafer Bump Material
<input type="checkbox"/>	Wafer Fab Site	<input type="checkbox"/>	Wafer Fab Materials
<input type="checkbox"/>		<input type="checkbox"/>	Part number change
<input checked="" type="checkbox"/>		<input type="checkbox"/>	Assembly Materials
<input type="checkbox"/>		<input type="checkbox"/>	Mechanical Specification
<input type="checkbox"/>		<input type="checkbox"/>	Test Process
<input type="checkbox"/>		<input type="checkbox"/>	Wafer Bump Process
<input type="checkbox"/>		<input type="checkbox"/>	Wafer Fab Process

PCN Details

Description of Change:

Texas Instruments is pleased to announce the qualification of a new lead frame base material for the devices listed below as follows:

	Current	New
Lead frame Base Material	MF202	C194

All other BOM elements will remain the same.

Reason for Change:

Continuity of Supply

Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:

None

Product Affected

ADS932E/2K	PCM1731E/2K	PCM1796DBR	PCM2903E
DF1704E	PCM1732U	PCM1798DB	PCM2904D1DB
DF1706E	PCM1732U/1K	PCM1798DBR	PCM2904D1DBR
DIR1701E	PCM1737E	PCM1800E	PCM2904DB
DIR1703E	PCM1737E/2K	PCM1800E/2K	PCM2904DBR
DIR1703E/2K	PCM1738E	PCM1802DB	PCM2906BDB
DSD1791DB	PCM1738E/2K	PCM1802DBR	PCM2906BDBR
DSD1791DBR	PCM1738EG-3/2K	PCM1803ADB	PCM2906CDB
DSD1792ADB	PCM1739E	PCM1803ADB	PCM2906CDBR
DSD1792ADB	PCM1739E/2K	PCM1803DB	PCM2906DB
DSD1792DB	PCM1740E	PCM1803DBR	PCM3000E
DSD1792DBR	PCM1740E/2K	PCM1804DB	PCM3000E/2K
DSD1793DB	PCM1745E/2K	PCM1804DBR	PCM3001E

DSD1793DBR	PCM1770PW	PCM1804S1DBR	PCM3001E/2K
DSD1794ADB	PCM1770PWR	PCM2702E	PCM3002E
DSD1794ADBR	PCM1770RGA	PCM2702E/2K	PCM3002E/2K
DSD1794DB	PCM1770RGAR	PCM2704DB	PCM3002EG
DSD1796DB	PCM1771PW	PCM2704DBR	PCM3002EG/2K
DSD1796DBR	PCM1771PWR	PCM2705DB	PCM3003E
PCM1606E	PCM1771RGA	PCM2705DBR	PCM3003E/2K
PCM1606E/2K	PCM1772PW	PCM2900BDB	PCM3008T
PCM1606EG/2K	PCM1772PWR	PCM2900BDBR	PCM3008T/2K
PCM1716E	PCM1772RGA	PCM2900CDB	PCM3008TG/2K
PCM1716E/2K	PCM1772RGAR	PCM2900CDBR	PCM3010DB
PCM1716EG	PCM1773PW	PCM2900E	PCM3010DBR
PCM1716EG/2K	PCM1773PWR	PCM2900E-P	PCM3052ARTF
PCM1717E	PCM1773RGA	PCM2900E/2K	PCM3052ARTFR
PCM1717E/2K	PCM1791ADB	PCM2901E	PCM3500E
PCM1718E	PCM1791ADBR	PCM2901E/2K	PCM3500E/2K
PCM1718E/2K	PCM1792ADB	PCM2902BDB	PCM3501E
PCM1720E	PCM1792ADBR	PCM2902BDBR	PCM3501E/2K
PCM1720E/2K	PCM1792DB	PCM2902CDB	PLL1700E
PCM1723E	PCM1792DBR	PCM2902CDBR	PLL1700E/2K
PCM1723E/2K	PCM1793DB	PCM2902E	PLL1700EG
PCM1727E	PCM1793DBR	PCM2902E/2K	PLL1700EG/2K
PCM1728E	PCM1794ADB	PCM2903BDB	VSP2272M/2K
PCM1728E/2K	PCM1794ADBR	PCM2903BDBR	VSP2582ARHNR
PCM1730E	PCM1794DB	PCM2903CDB	VSP2582RHNR
PCM1730E-1/2K	PCM1794DBR	PCM2903CDBR	VSP2582RHNR
PCM1731E-1/2K	PCM1796DB		



TI Information
Selective Disclosure

Qualification Report

Lead Frame Base Material Qualification : C194 for the
VSP5100PDT
Approved 10/25/2014

Product Attributes

Attributes	Qual Device: VSP5100PDT	QBS Product/Package: VSP5100PDT
Assembly Site	NST	NST
Package Family	TQFP	TQFP
Flammability Rating	UL 94 V-0	UL 94 V-0
Wafer Fab Site	VANGUARD	VANGUARD
Wafer Fab Process	0.35UM 2P3M	0.35UM 2P3M

- QBS: Qual By Similarity
- Qual Device VSP5100PDT is qualified at LEVEL3-260C

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: VSP5100PDT	QBS Product/Package: VSP5100PDT
UHAST	Unbiased HAST 130C/85%RH	96 Hours	2/160/0	-
TC	Temperature Cycle, -65/150C	500 Cycles	2/160/0	3/77/0
SD	Solderability	PB-Free	2/44/0	-
LI	Lead Finish Adhesion	Leads	2/30/0	-
HTOL	High Temperature Life Test, 125C	1000 Hours	-	3/120/0
HAST	Biased HAST 130C/85%RH	96 Hours	-	3/77/0
TC	Temperature Cycle, -65/150C	500 Cycles	-	3/77/0
ESD	ESD-HBM	2000V	-	1/3/0
ESD	ESD-CDM	500V	-	1/3/0
LU	Latch-up	Per JESD78	-	1/6/0

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

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USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
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